



# DPG 2010 – T60.3

## Extraction of Parasitic RC Parameters of a DEPFET Pixel Matrix

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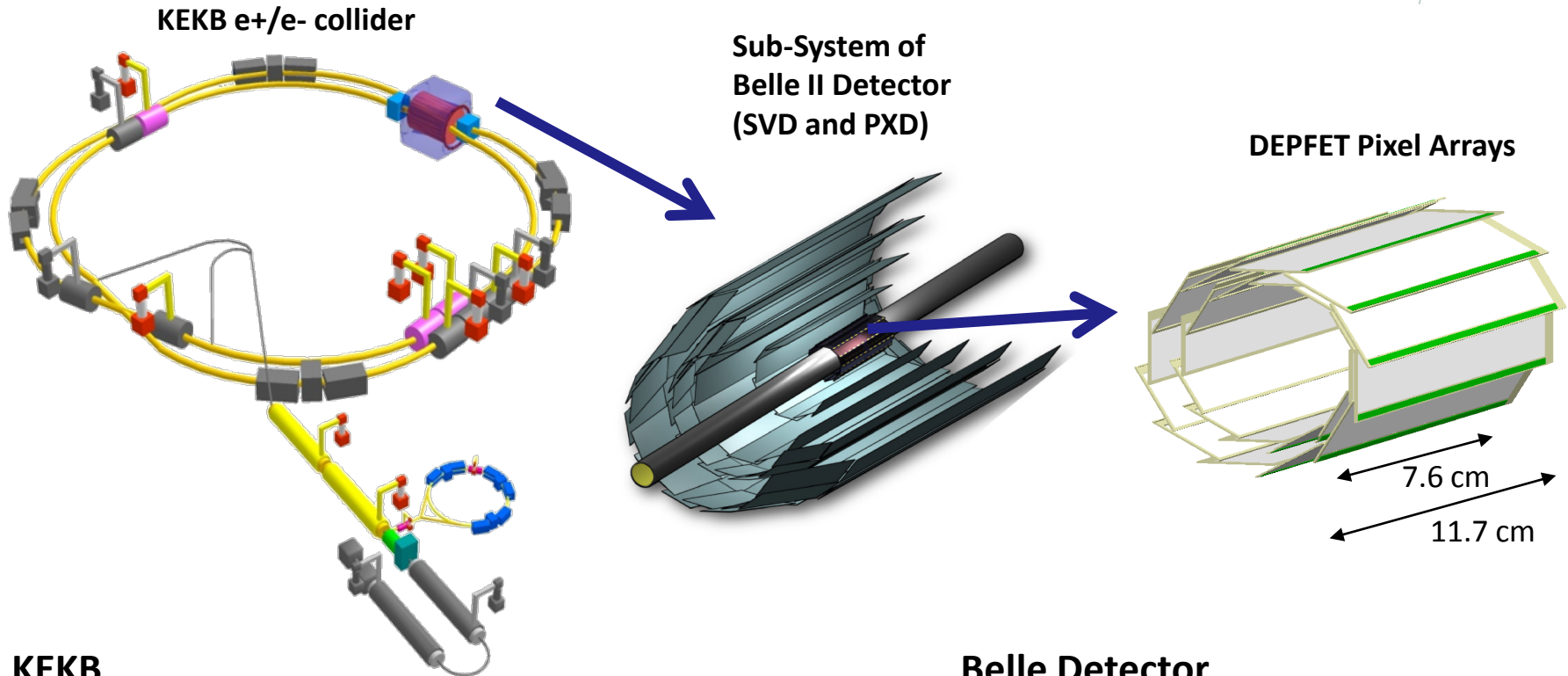
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# ● Overview



- DEPFET Pixel in the Belle-II Detector @ SuperKEKB
- DEPFET Pixel and Operation Principle
- DEPFET Pixel Matrix – Array Layout
- Why Parasitic RC Parameter Extraction?
- Method and Tools of the Parasitic Extraction
- First Results of DEPFET Matrix Simulation incl. Parasitic RCs
- Summary & Outlook

# ● DEPFET PXD for Belle II Detector @ SuperKEKB



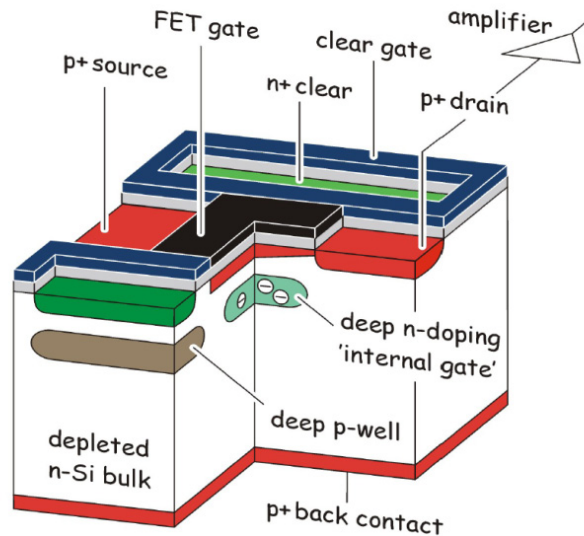
## KEKB

- Aims to prove CP-violations in the B meson/anti-B meson decay (CP = charge-parity)
- Upgrade of KEKB to improve the rate of particle collisions by a factor of 40

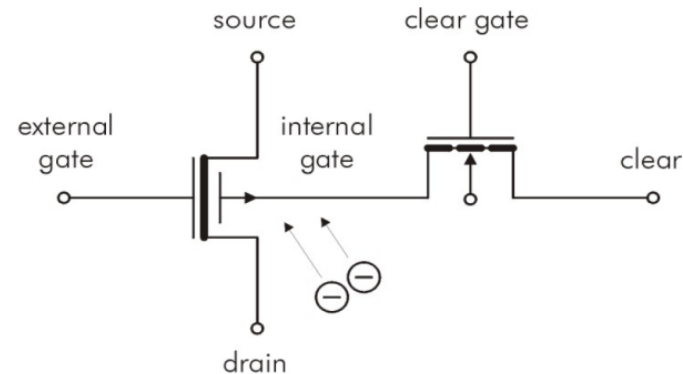
## Belle Detector

- Detection of particles which result from the e+/e- collision
- SVD: 4 layers of double sided silicon strip sensors
- PIX: 2 layers of DEPFET pixel detectors

# DEPFET Pixel and Operation Principle



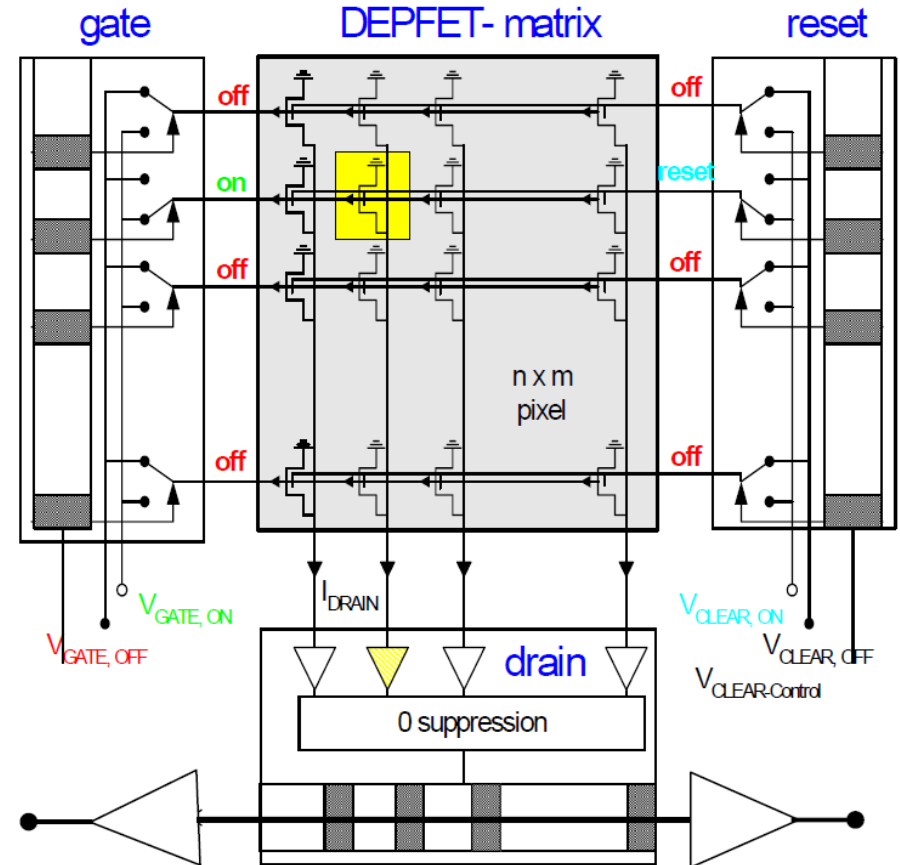
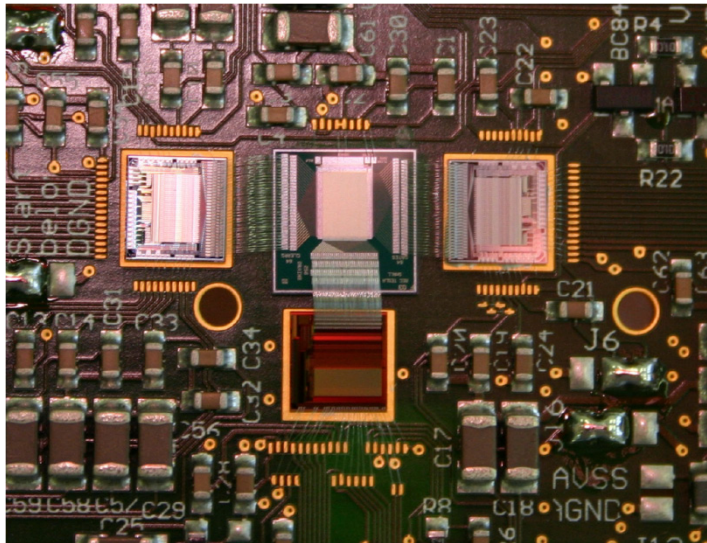
J. Kemmer & G. Lutz, 1987



- DEPFET is an acronym for depleted p-channel field effect transistor
- Collection of electrons within the internal gate
- Modulation of the FET current by the charge in the internal gate
- Fully depleted sensitive volume
- Charge collection in the transistor "off" state, read out on demand
- Clear contact to empty the internal gate

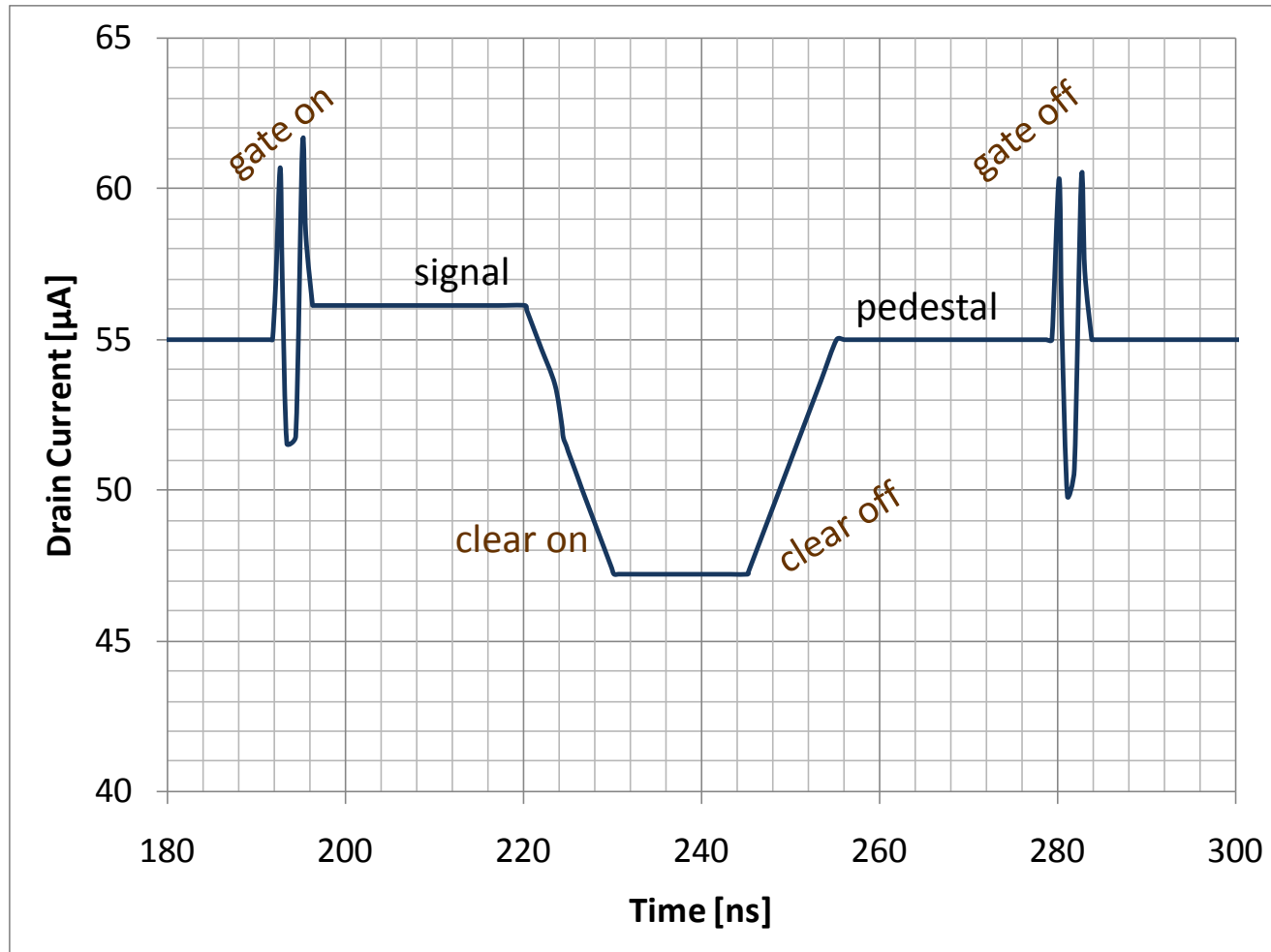
# DEPFET Pixel Matrix

- Row wise read-out ("rolling shutter,")
- Correlated double sampling and single sampling possible
- auxiliary ASICs needed for row selection, clear and current read-out



# ● Why Parasitic RC Parameter Extraction?

Simulation of the drain current of a DEPFET matrix without parasitic RCs.

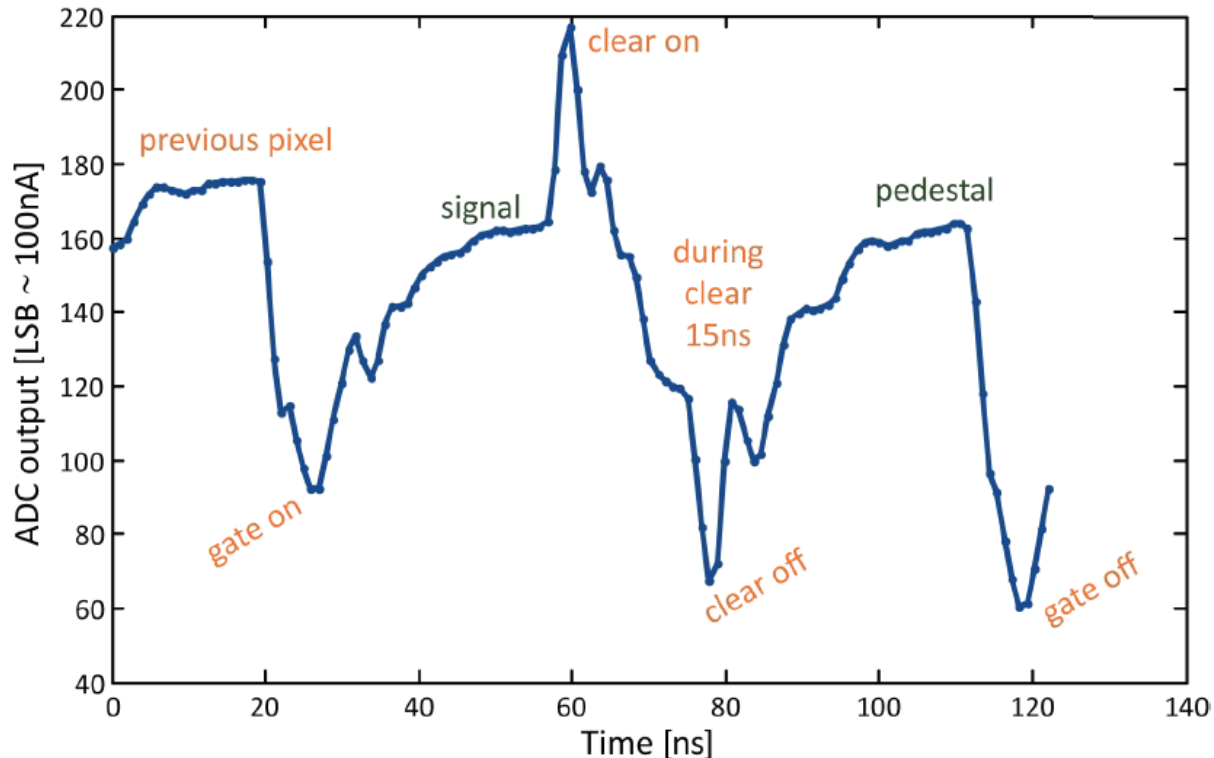


Simulation tool: Cadence SpectreCMI, T Gate on = 90ns

# ● Why Parasitic RC Parameter Extraction?

## Time resolved DEPFET output current (maximum speed so far)

single pixel DEPFET (COG LE) current output as seen by DCD  
row-rate 10.83MHz (92.3ns)



- no longer good settling behavior!
- sampling steps now 0.96ns

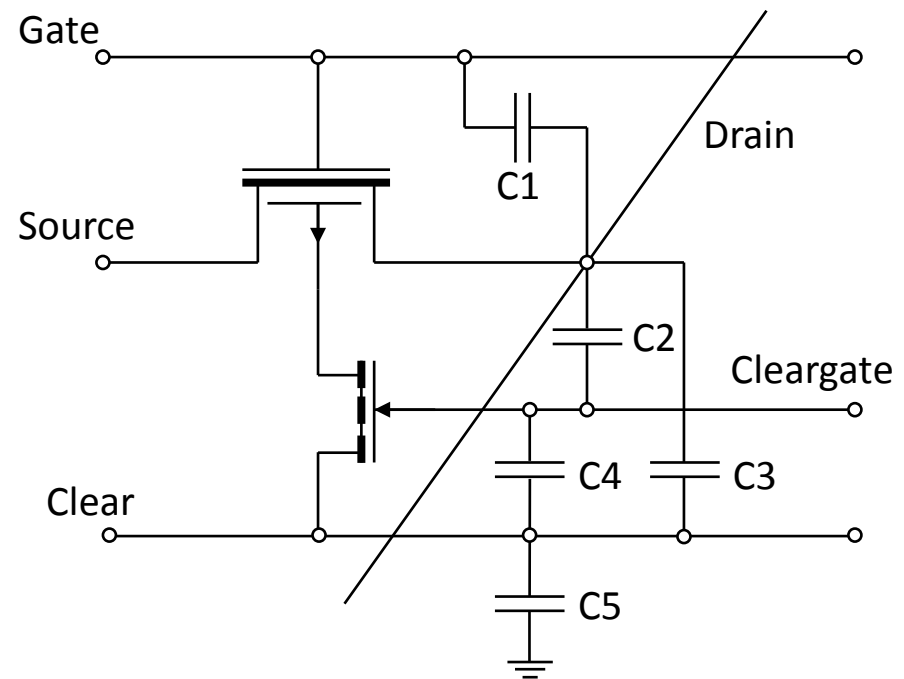
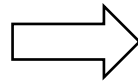
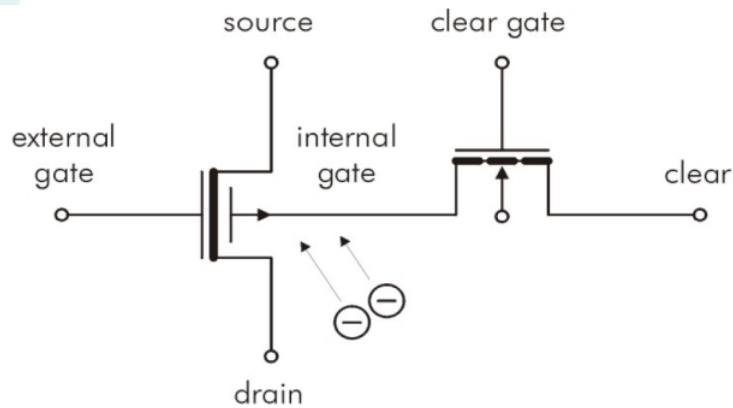
Measurement of a DEPFET matrix by Manuel Koch

# ● Why Parasitic RC Parameter Extraction?

→ Include coupling to neighboring drain, gate and clear lines

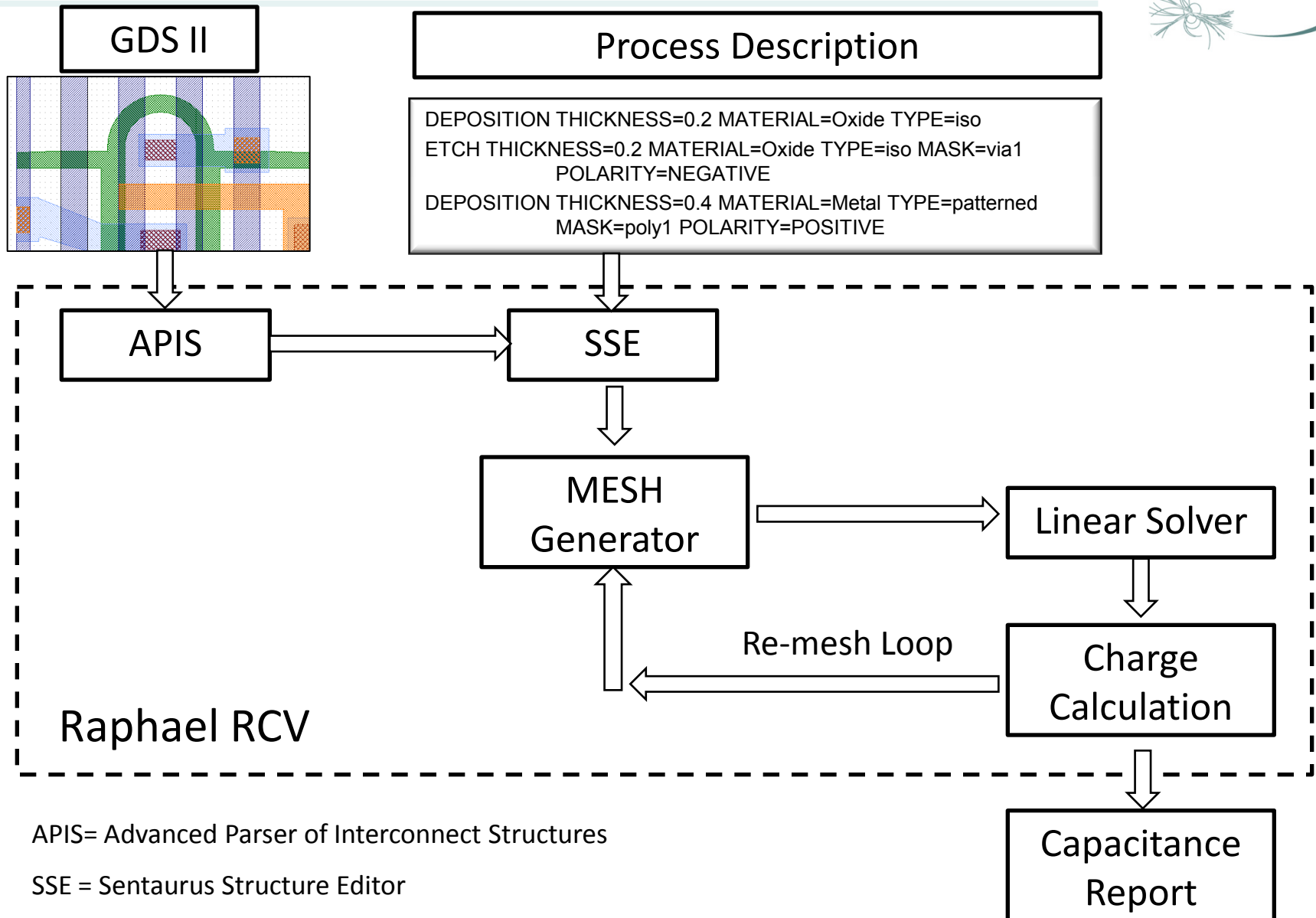
→ Belle-II DEPFET Pixel Matrix will have the dimensions of approx.  $1 \times 4 \text{ cm}^2$

→ Simulation of the different designs options (Capacitive Coupled Cleargate)



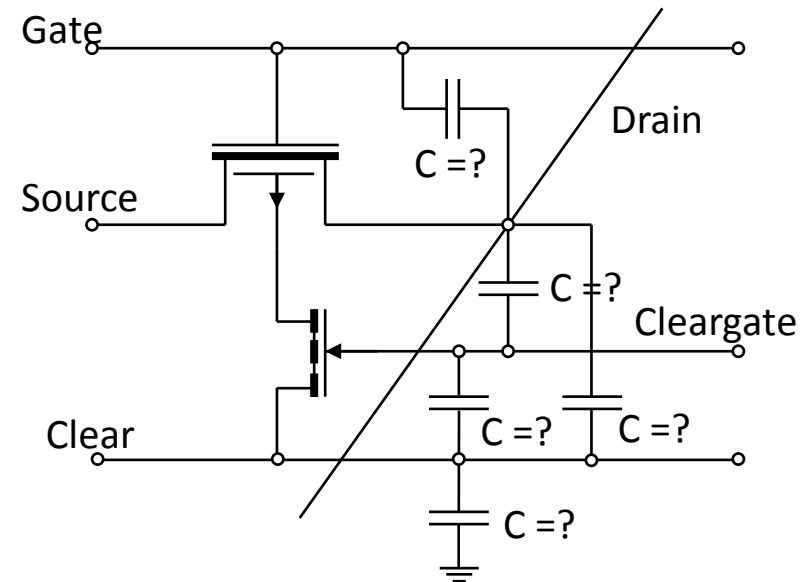


# ● Synopsys Raphael RCV + Sentaurus Structure Editor



# ● Capacitance Report

cap label	net1	net2	cap [fF]																							
C1_0	gate	drain1	31.9																							
C2_0	gate	drain2	60.3																							
C3_0	gate	drain3	67.4																							
C4_0	gate	drain4	63.0																							
C5_0	gate	drain5	51.6																							
C6_0	gate <td drain6	67.4	C7_0	gate	drain7	60.3	C8_0	gate	drain8	31.9	C9_0	gate	source	28.4	C10_0	gate	clear	53.4	C11_0	gate	cleargate	24.6	C0_g	gate	GND	22.1
C7_0	gate	drain7	60.3																							
C8_0	gate	drain8	31.9																							
C9_0	gate	source	28.4																							
C10_0	gate	clear	53.4																							
C11_0	gate	cleargate	24.6																							
C0_g	gate	GND	22.1																							



# ● Technology Simulation using Sentaurus Structure Editor

## ■ Double poly/double aluminum process

### Process Description

DEPOSITION THICKNESS=0.2 MATERIAL=Oxide  
TYPE=iso

DEPOSITION THICKNESS=0.4 MATERIAL=Metal  
TYPE=patterned MASK=poly1  
POLARITY=POSITIVE

DEPOSITION THICKNESS=0.2 MATERIAL=Oxide  
TYPE=iso

DEPOSITION THICKNESS=0.4 MATERIAL=Metal  
TYPE=patterned MASK=poly2  
POLARITY=POSITIVE

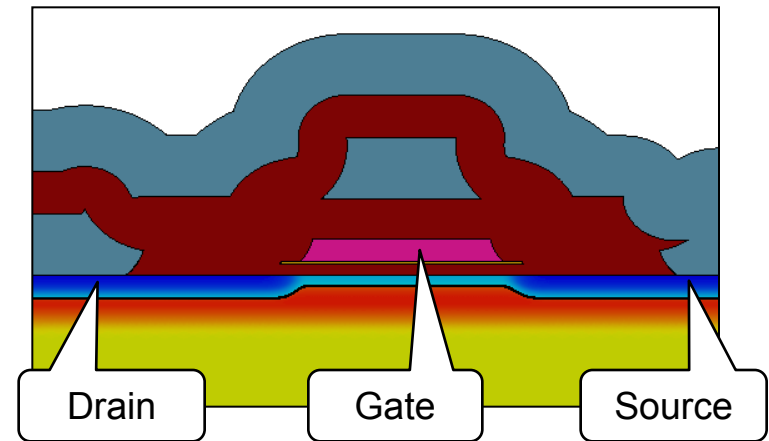
DEPOSITION THICKNESS=0.300 MATERIAL=Oxide  
TYPE=iso

ETCH THICKNESS=0.5 MATERIAL=Oxide TYPE=iso  
MASK=via1 POLARITY=NEGATIVE

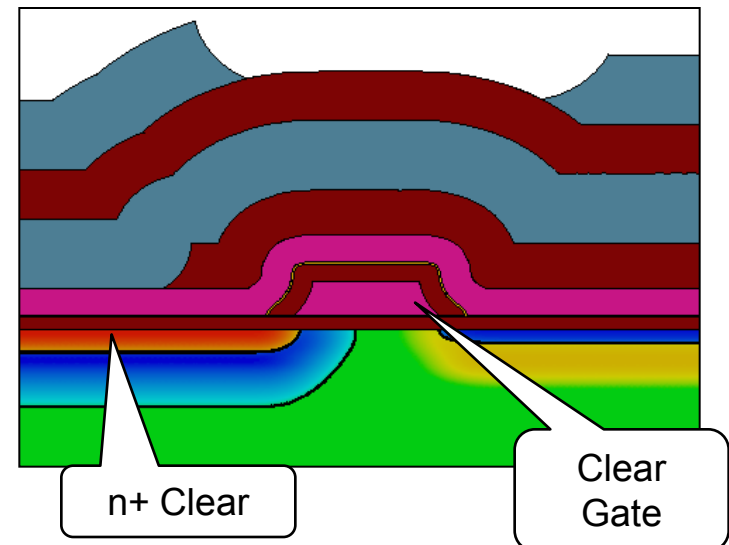
DEPOSITION THICKNESS=0.4 MATERIAL=Metal  
TYPE=patterned MASK=metal3  
POLARITY=POSITIVE

CAPACITANCE gate drain8 drain7 drain6 drain5 drain4  
drain3 drain2 drain1 source cleargate clear

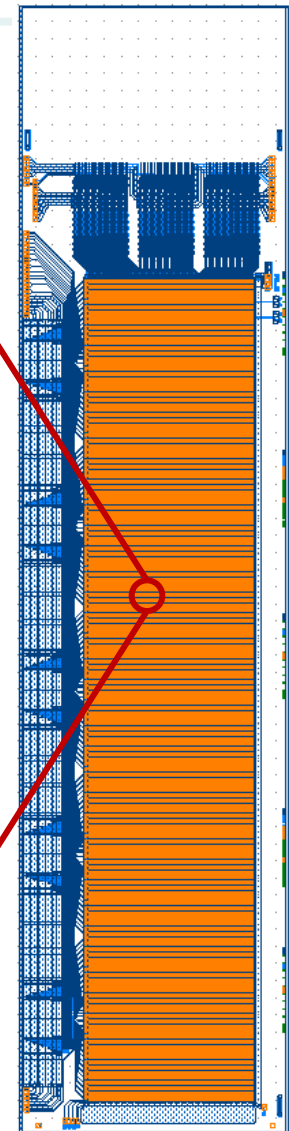
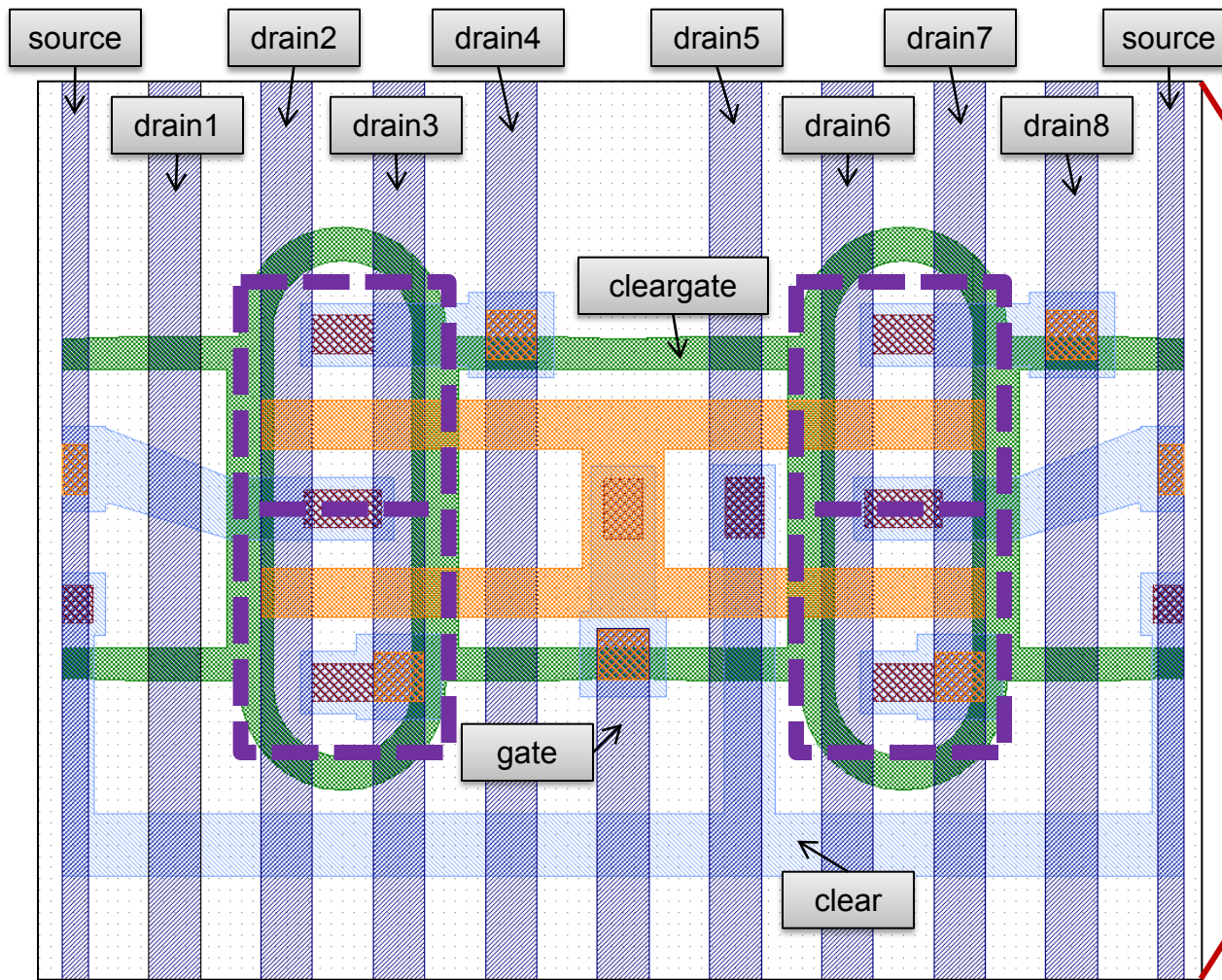
Along P-Channel



Perpendicular to Channel (with CLEAR)

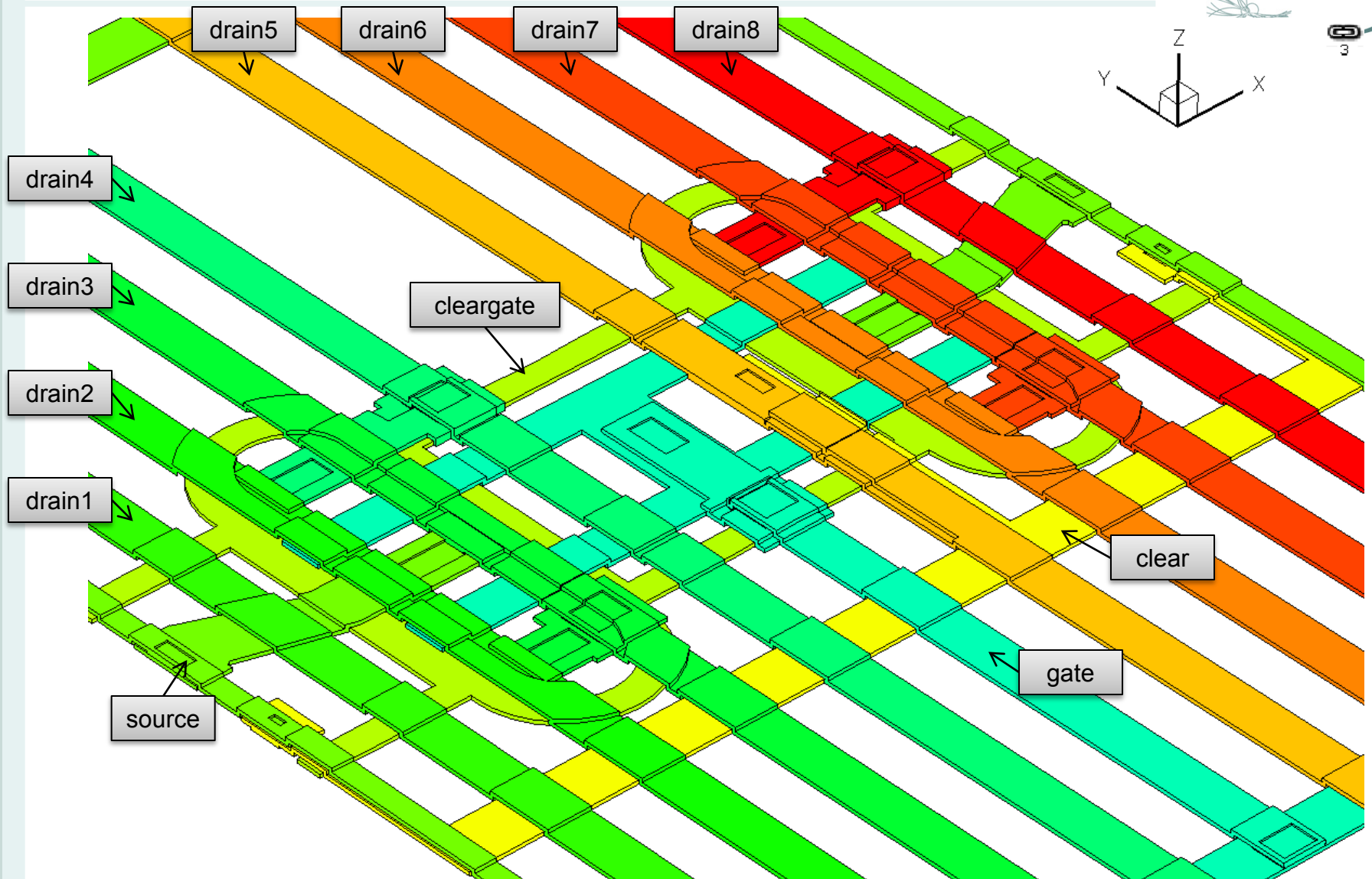


# ● Detail of a DEPFET Layout

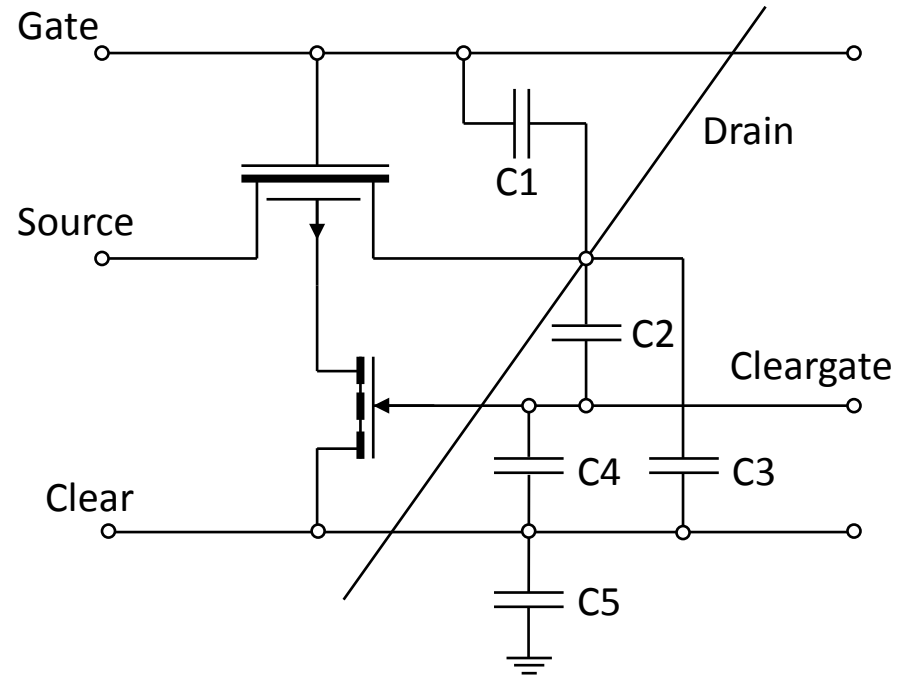
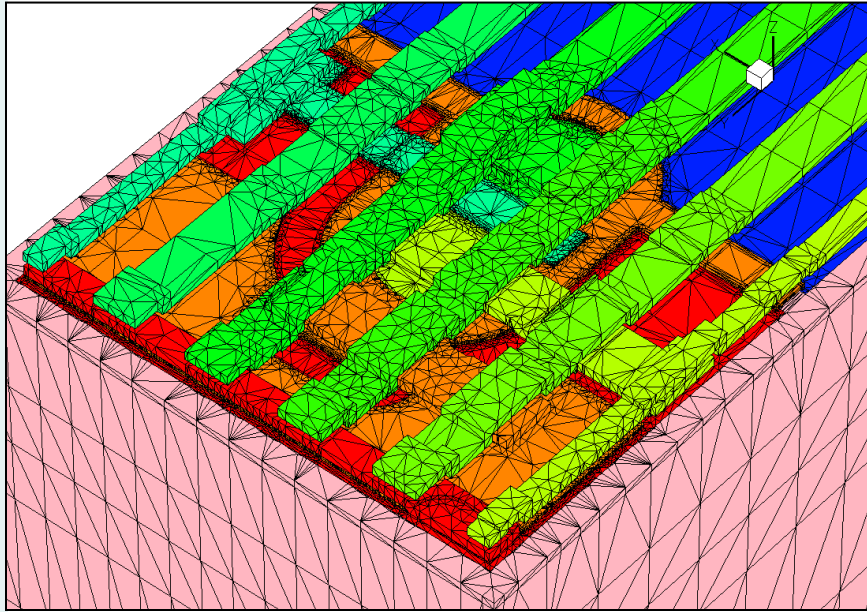


4 Pixel Sub-Circuit

# 3D Geometrical Model



# Results for a Capacitive Coupled Clear Gate Pixel



cap label	net1	net2	cap [fF]
C1	Gate	Drain	8.7
C2	Cleargate	Drain	17
C3	Clear	Drain	4.5
C4	Clear	Cleargate	167
C5	Clear	All except cleargate	56

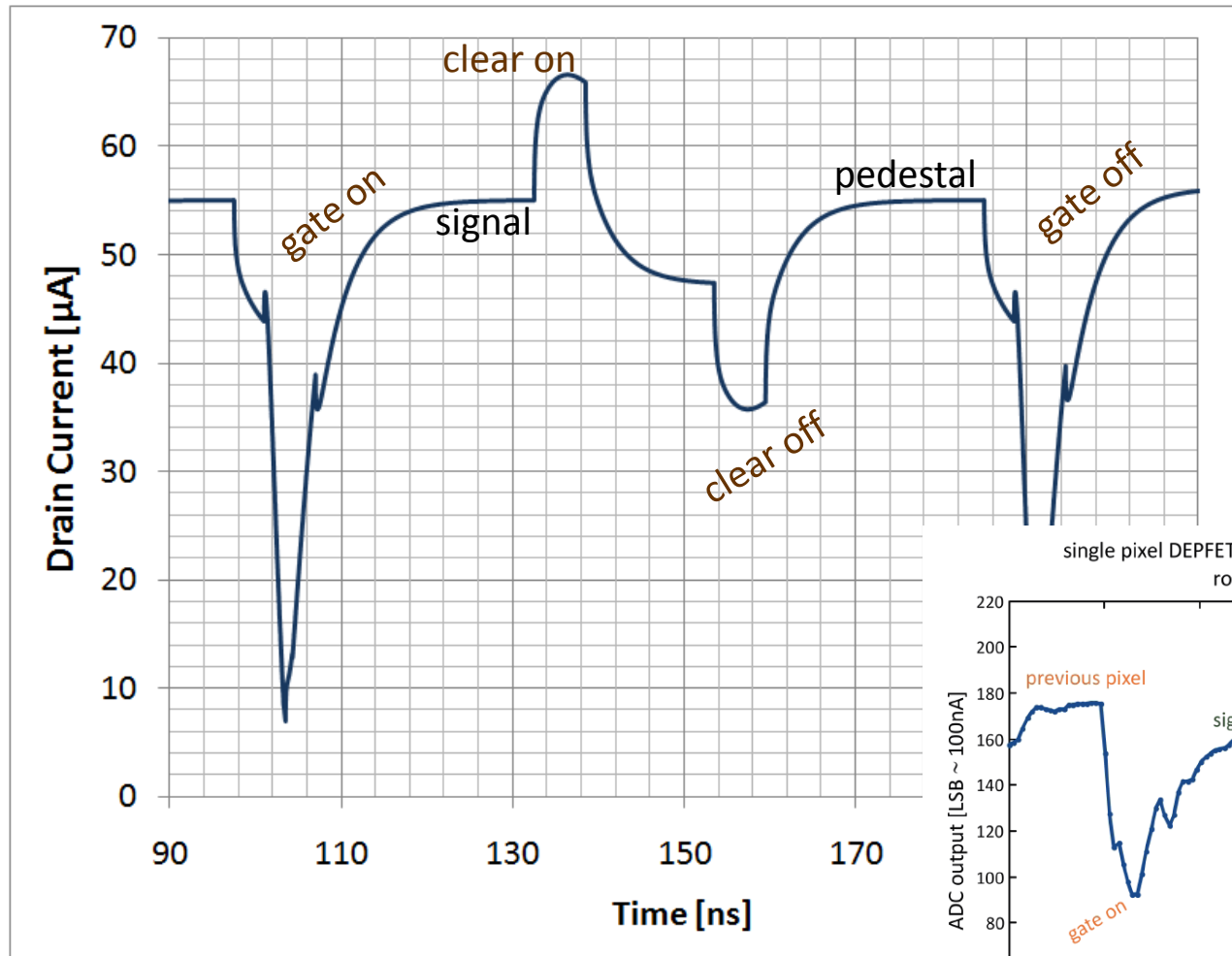
For a pixel array 768x160:

$$C_{\text{clear\_array}} = 100 * 223\text{fF} = 22\text{pF}$$

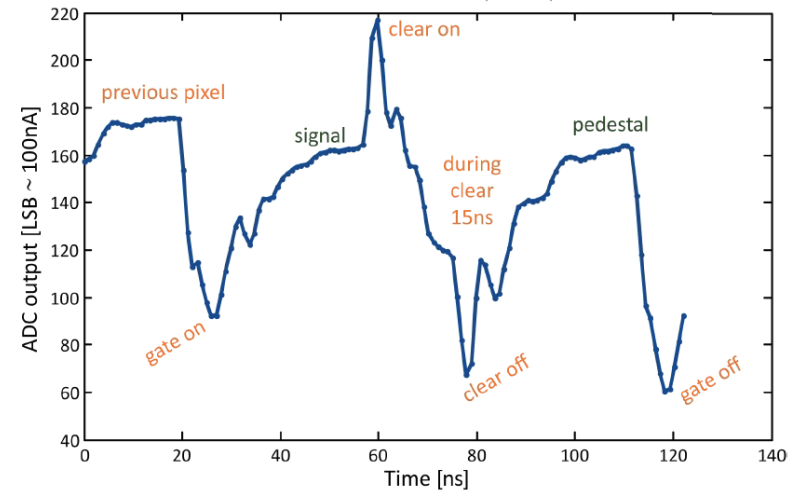
Number of layout cells per row.

# DEPFET Matrix Simulation including RC

**PRELIMINARY**



single pixel DEPFET (COG LE) current output as seen by DCD  
row-rate 10.83MHz (92.3ns)



# ● Summary and Outlook



- Work flow for the extraction of the parasitic RC parameters of DEPFET matrix designs has been established
  - based on layout files
  - including non-planar technology
- Extraction of the Clear-Cleargate capacitance of different design was performed for the current prototype production
- Improvement of the DEPFET model incl. different pixel cell designs and matrix designs is ongoing



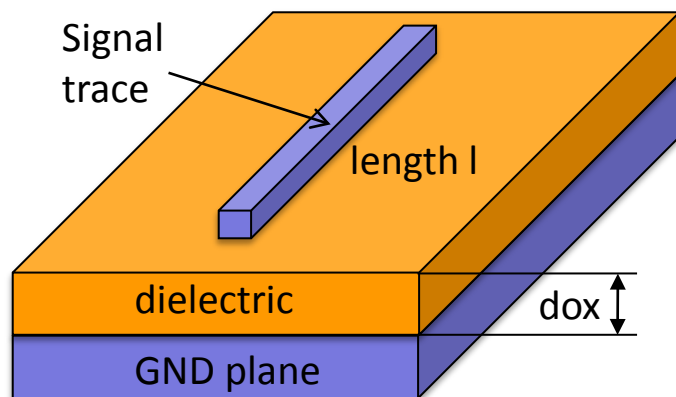
Thank you!

# ● Model Validation

- Validation of the Raphael Simulator using a 2D field simulators shows errors in the 5% range
- Example: 100μm long trace over GND plane with different oxide thickness

$$C = \epsilon_0 \cdot \epsilon_r \cdot \left[ 1.15 \cdot \left( \frac{w}{dox} \right) + 2.28 \cdot \left( \frac{d}{dox} \right)^{0.222} \right] \cdot l$$

from CMOS Logic Circuit Design, John P. Uyemura.

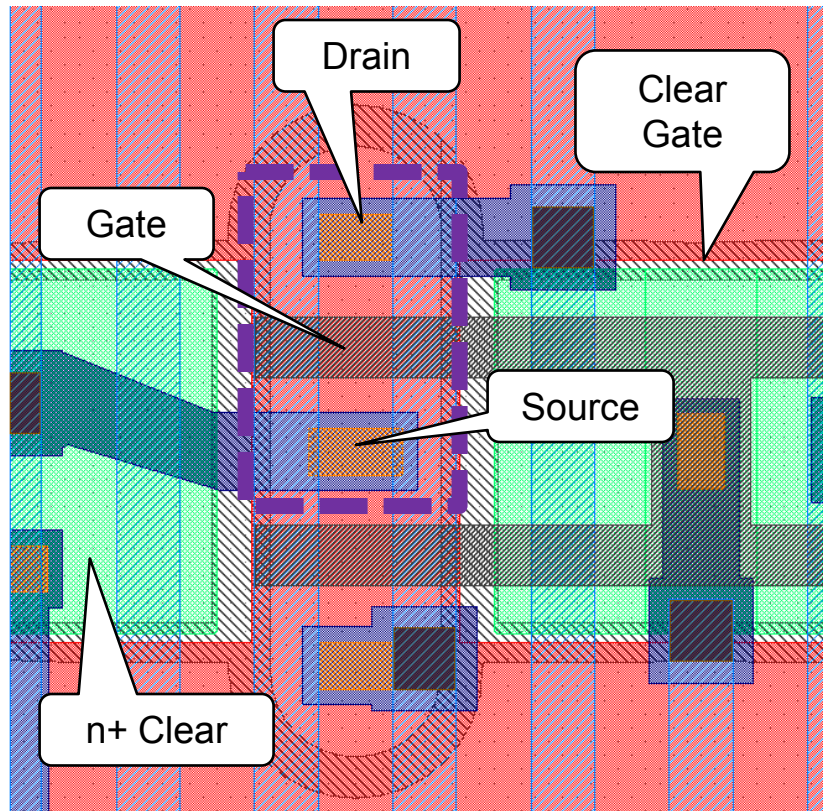


Simulation Result using Raphael RCV + Sentaurus Structure Editor

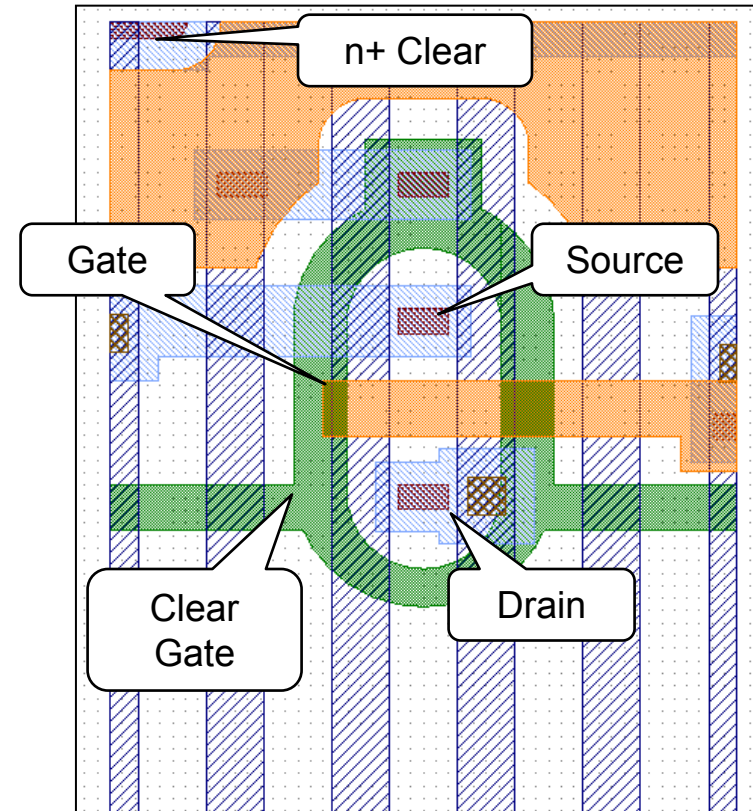
l [μm]	dox [nm]	C_calc [fF]	C_Raphael [fF]	error in %
100	100	52	55	7
100	200	30	33	11
100	400	18	21	12

# Examples of DEPFET Pixel Cell Layouts

## Common Cleargate DEPFET pixel



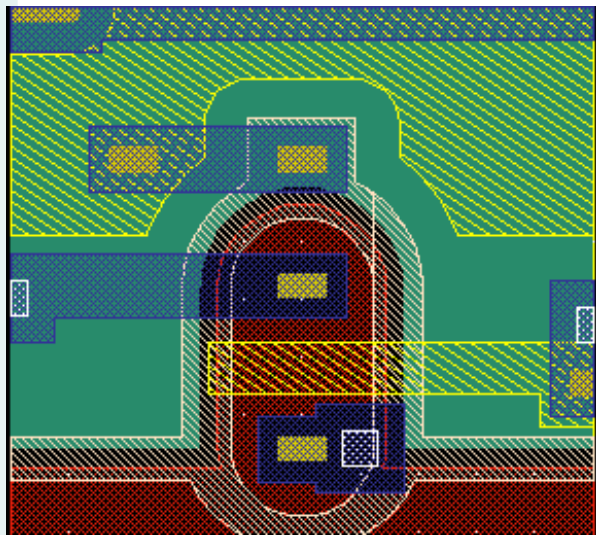
## Capacitively Coupled Cleargate DEPFET



- Small pixel size from  $20 \times 20 \mu\text{m}^2$  to  $50 \times 75 \mu\text{m}^2$
- High spatial resolution

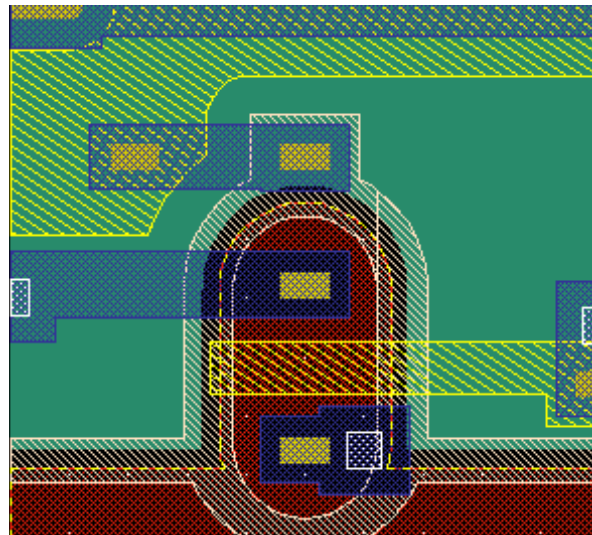
# ● Capacitive Coupled Cleargate Designs

## Different Poly2 Layouts for the Cleargate-Clear Capacitor



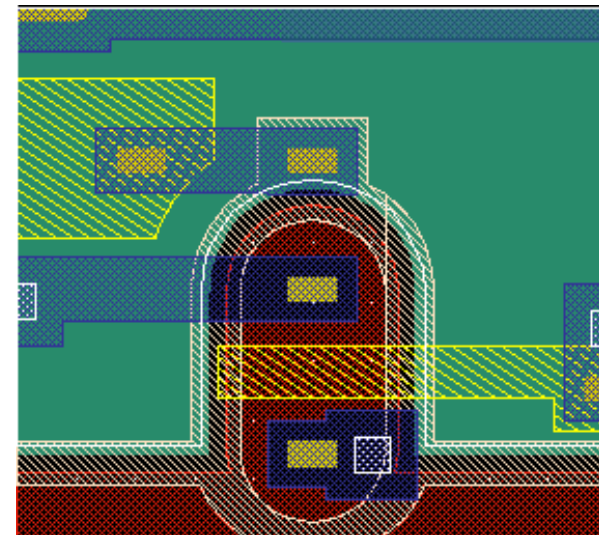
cap\_simu\_CC\_CD\_ED\_SCG\_Z100

Coupling Clear Cleargate: 68%



cap\_simu\_CC\_CD\_ED\_SCG\_Z100\_A

Coupling Clear Cleargate: 64%



cap\_simu\_CC\_CD\_ED\_SCG\_Z100\_B

Coupling Clear Cleargate: 51%

# ● Spice Model

**PRELIMINARY**

cap label	net1	net2	cap [F]
C1_0	gate	drain1	3.19E-15
C2_0	gate	drain2	6.03E-15
C3_0	gate	drain3	6.74E-15
C4_0	gate	drain4	6.3E-15
C5_0	gate	drain5	5.16E-15
C6_0	gate	drain6	6.74E-15
C7_0	gate	drain7	6.03E-15
C8_0	gate	drain8	3.19E-15
C9_0	gate	source	2.84E-15
C10_0	gate	clear	5.34E-14
C11_0	gate	cleargate	2.46E-14
C0_g	gate	GND	2.21E-13

For a pixel array 768x160 ST\_SD\_SCG\_Z075:

$$C_{\text{gate\_array}} = 100 * 3.45E-13F = 35pF$$

# DEPFET Pixel and Operation Principle

- based on the combination of the sideways depletion principle and field effect transistor principle
- charge collection by drift
- detects particles which traverse the substrate of the detector

